



REPLACEMENT DRAWING
Title: System And Method For Chip Testing
Inventor: Joseph Weiye Ku
HP PDNO.: 10008039-1
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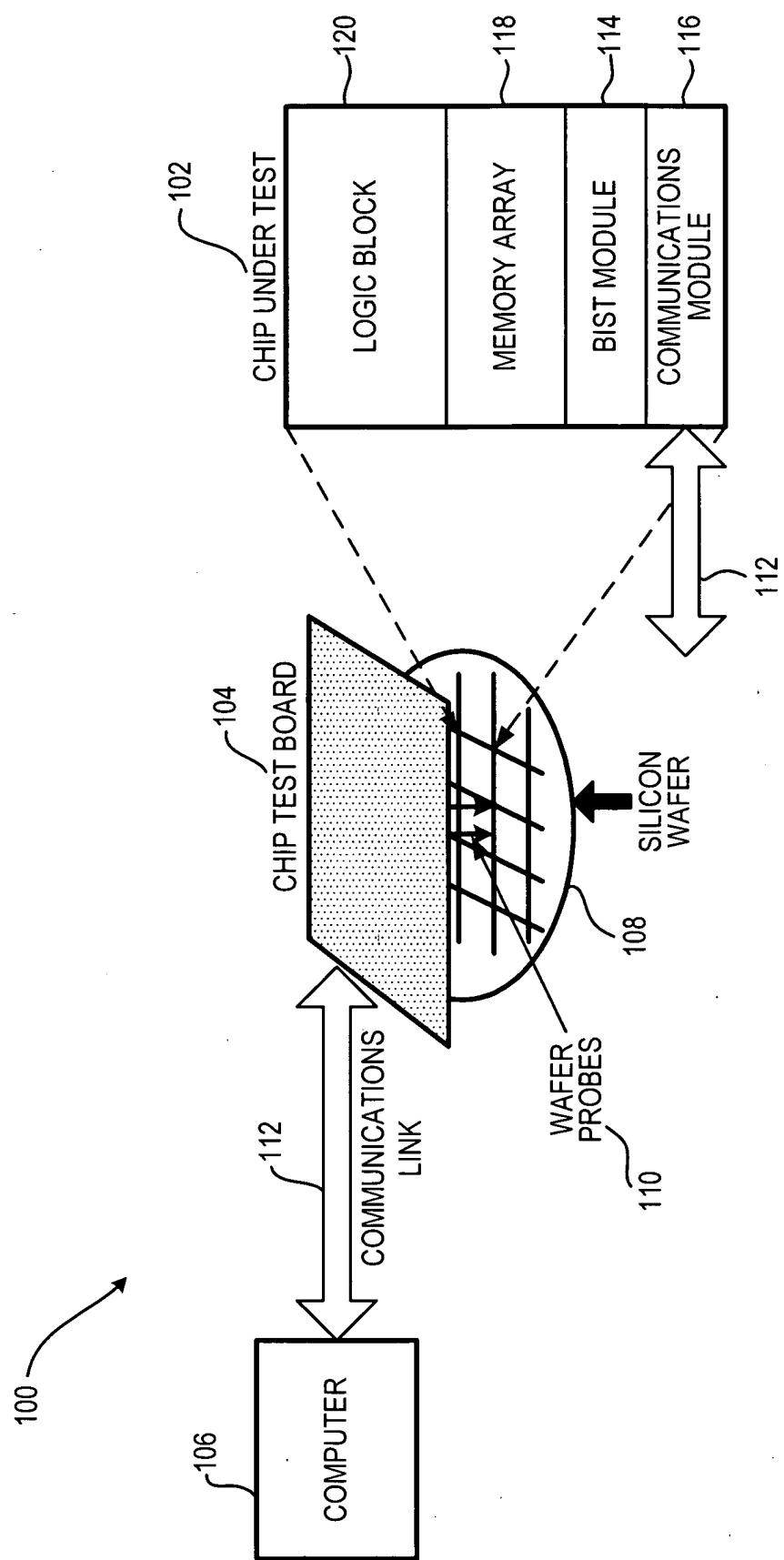


Fig. 1

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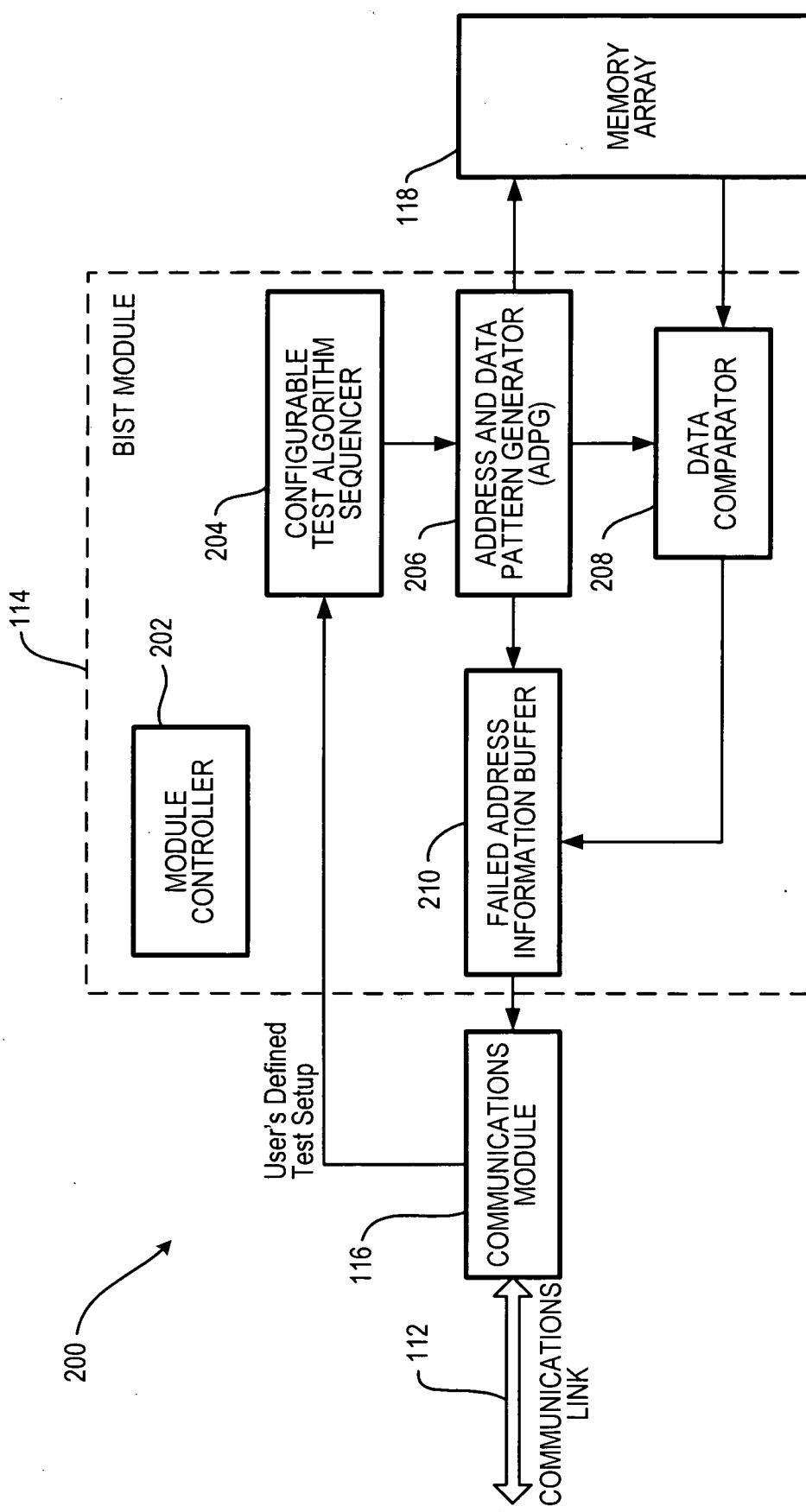


Fig. 2



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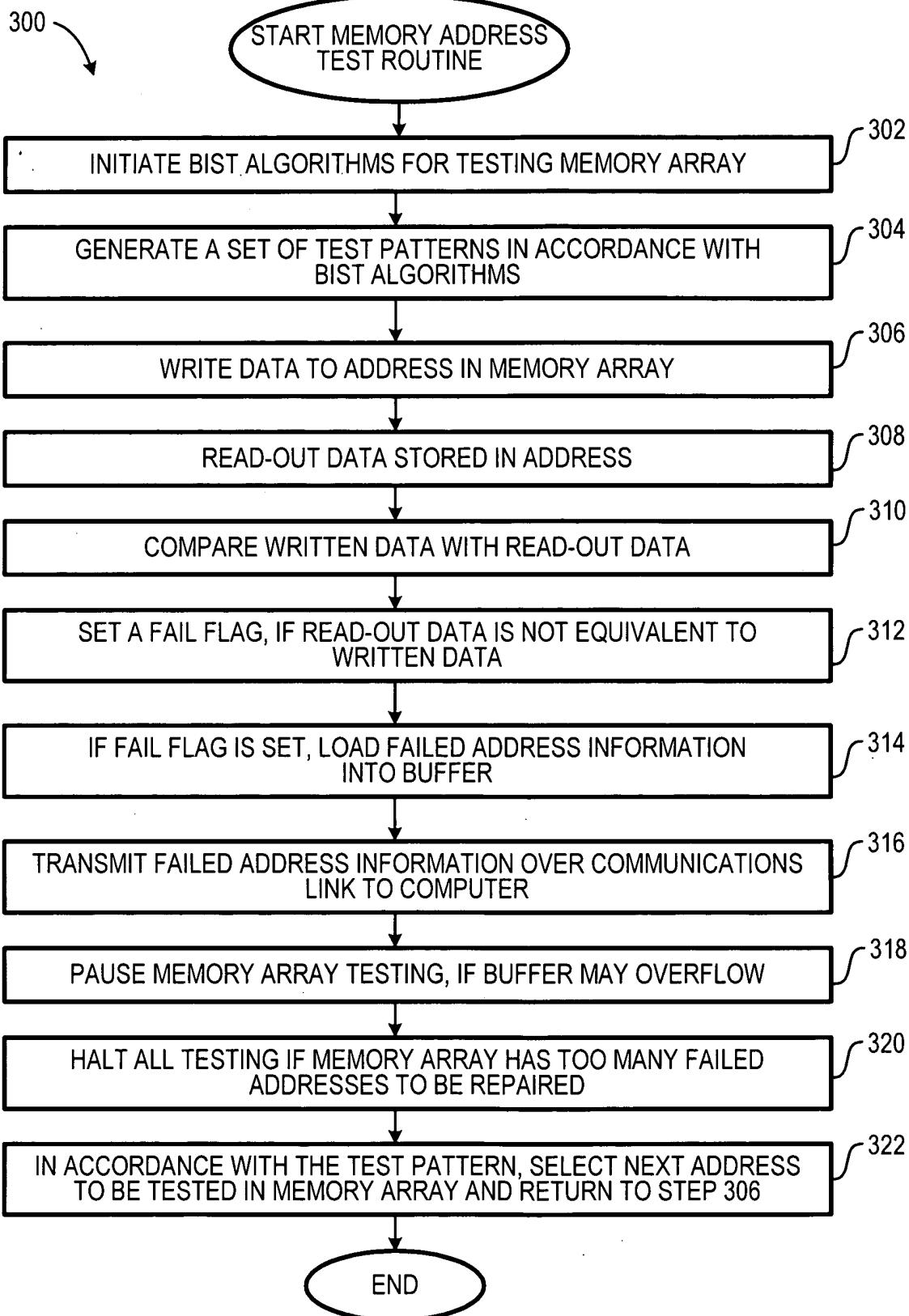


Fig. 3

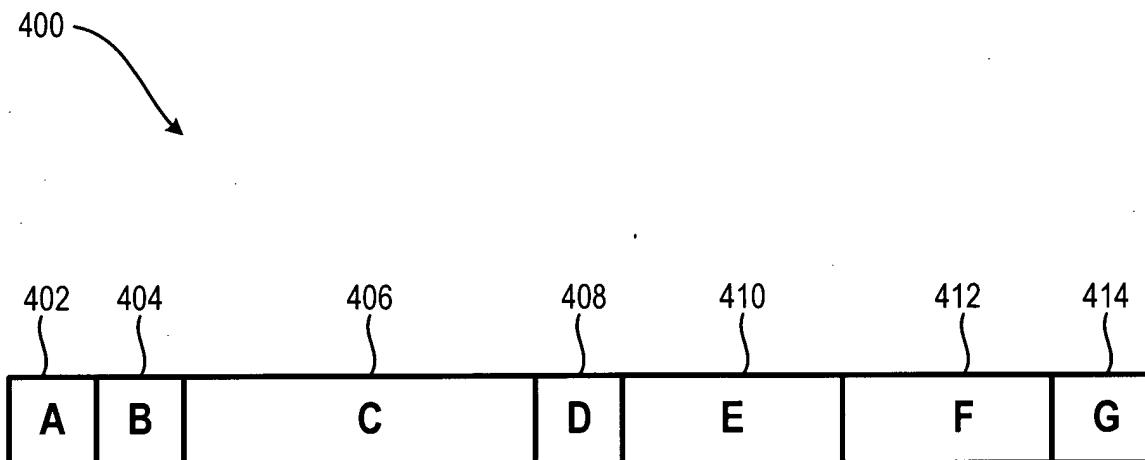


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FIELD:

DATA CONTENTS:

A	HEADER
B	FAILED ADDRESS LENGTH
C	FAILED ADDRESS
D	FAILED DATA LENGTH
E	DATA WRITTEN
F	DATA READ-OUT
G	FAILED BIT LOCATIONS

Fig. 4